



APEC 2026



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Mitigating False Turn-On in Power MOSFETs Using Current Mode Gate Drivers: Advancements in Gate Drive Control

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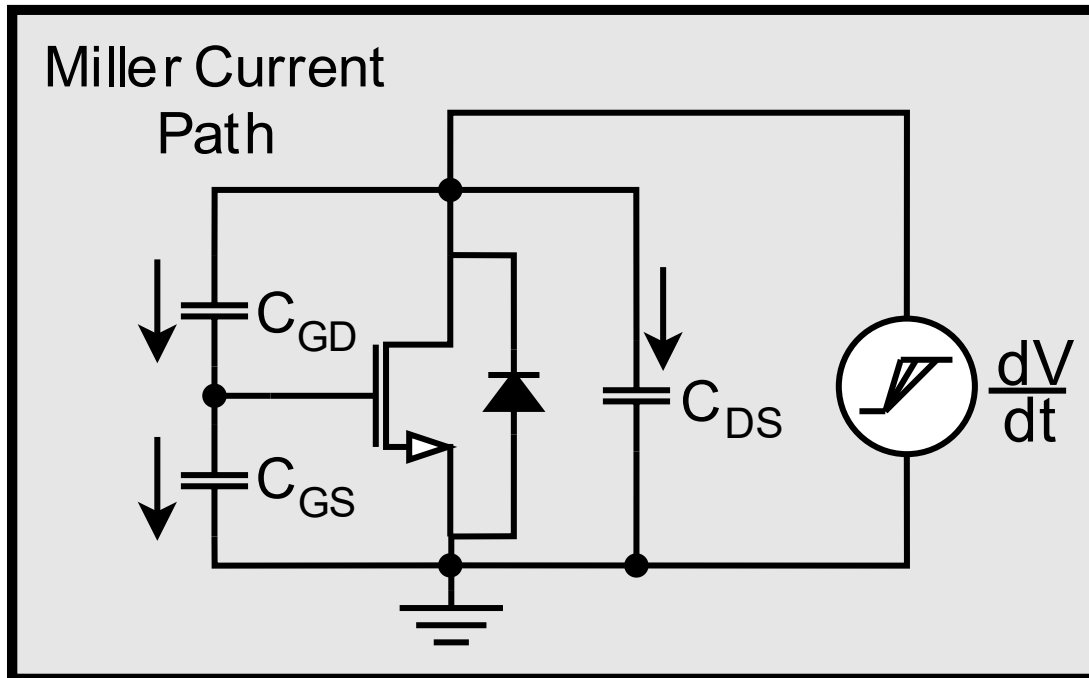


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Table of Contents

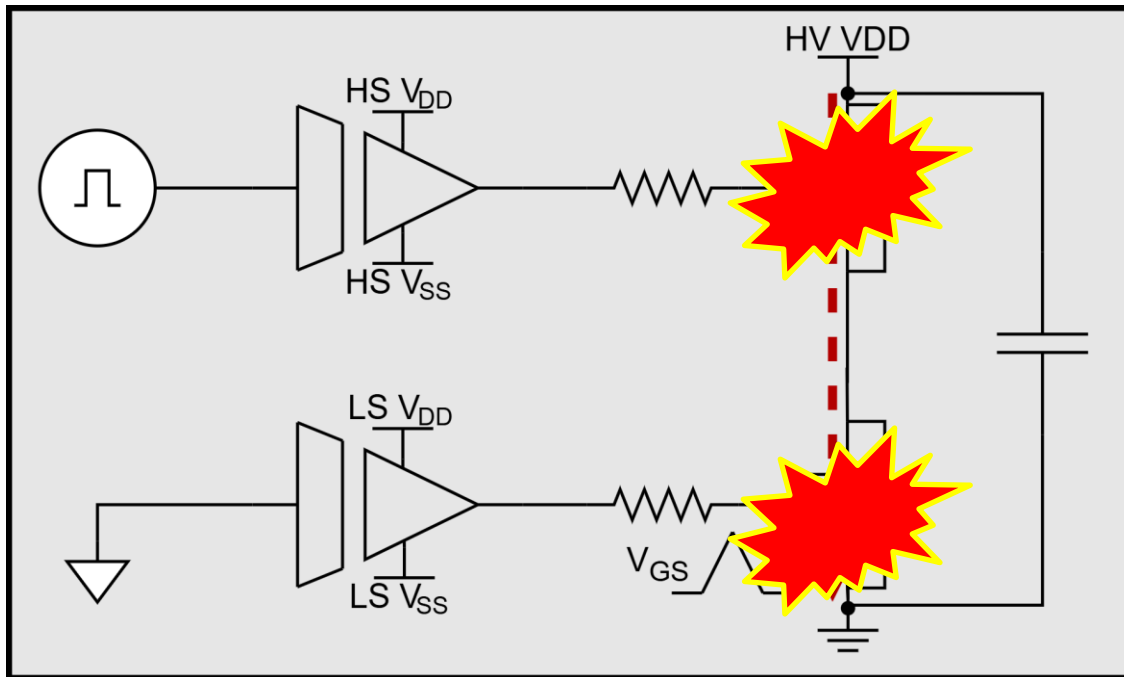
- Miller Clamp Background
- Parasitic Turn-On
- Introduction to Current Mode Gate Drivers
- Miller Clamp Engagement Profile
- Test Setup(s)
- Experimental Waveforms + Results
- Conclusions

Miller Capacitance and Parasitic Turn-On



- Miller capacitance (C_{GD}) causes a current to flow through $C_{GD} + C_{GS}$
- Approximately: $dV_{GS} \approx \frac{C_{GD}}{C_{GS}} dV_{DS}$
 - See appendix for derivation
- Capacitance ratio of $\frac{C_{GD}}{C_{GS}}$ determines susceptibility of parasitic turn-on (PTO)
- If $V_{GS} > V_{GS(TH)}$ then PTO can occur

Parasitic Turn On

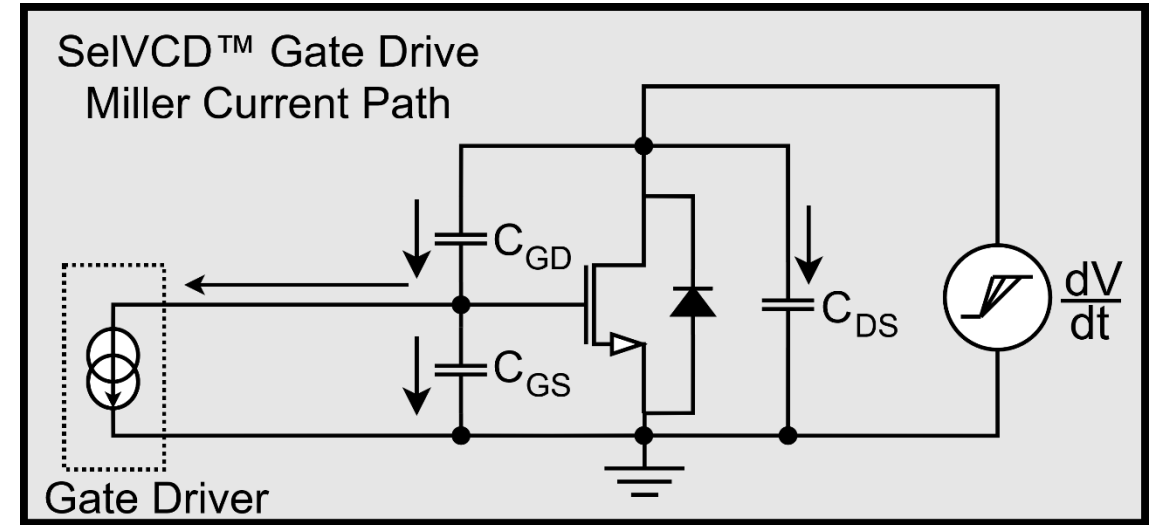
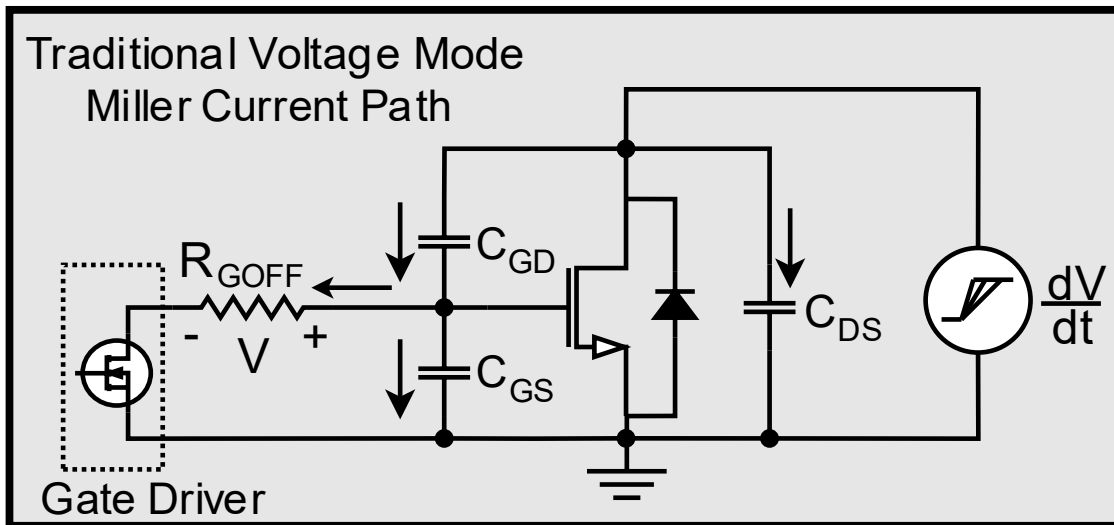


- PTO can cause fires
- Power supply design needs to consider all operating modes/conditions
- Power supply revisions are costly, especially if power supplies are already in the field

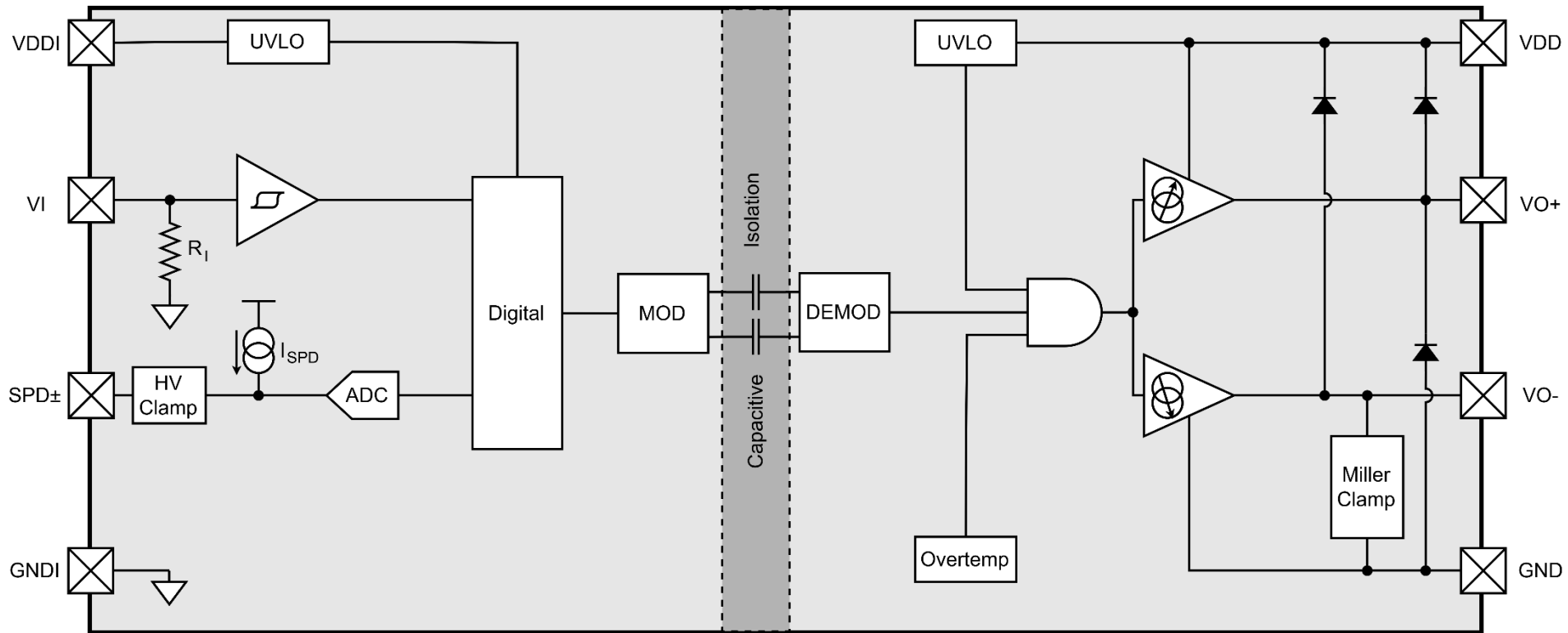
Miller Effect & Gate Drivers

R_{GOFF} Impedes flow

Current source has direct path

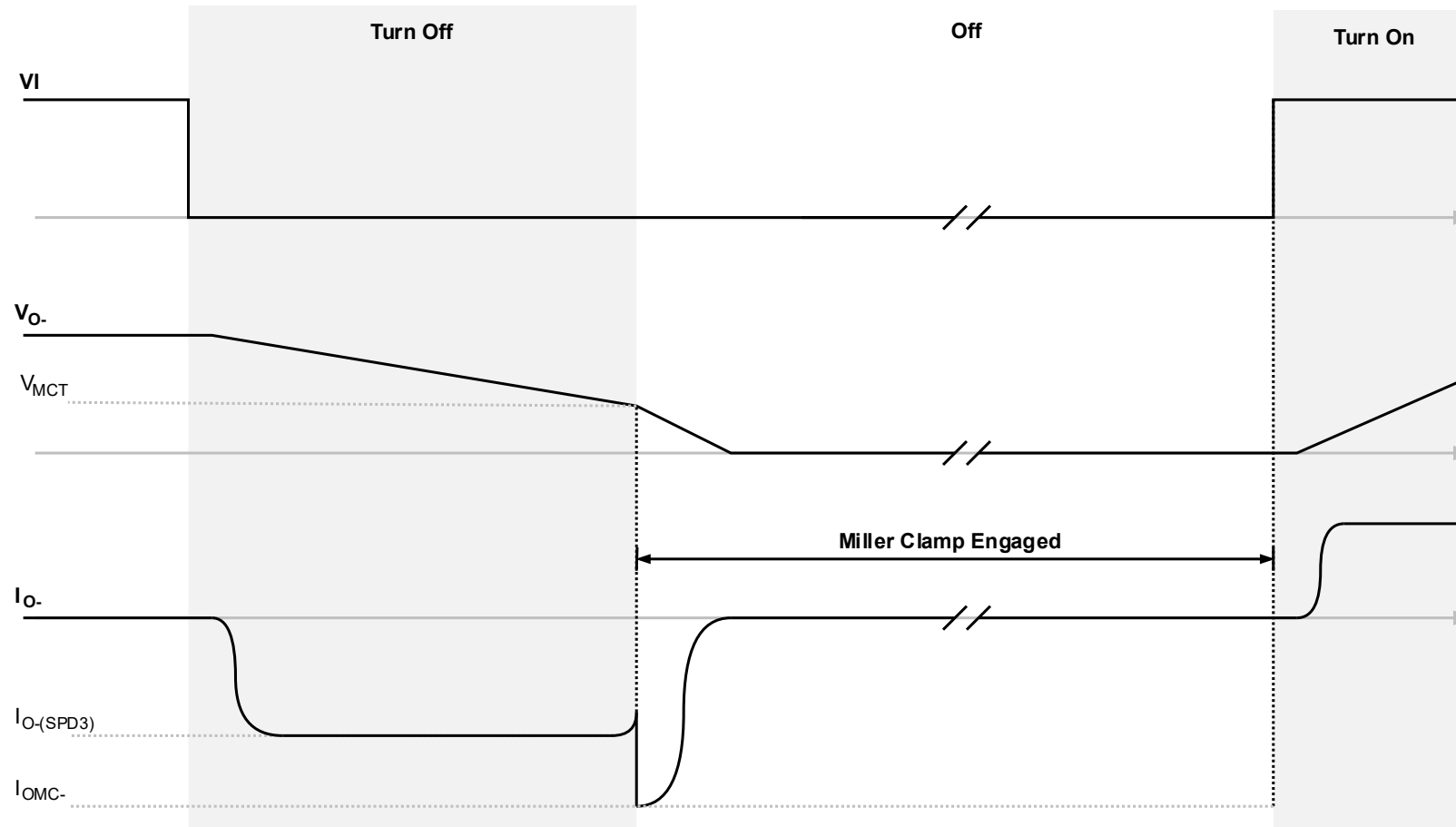


Inside a Current Mode Gate Driver



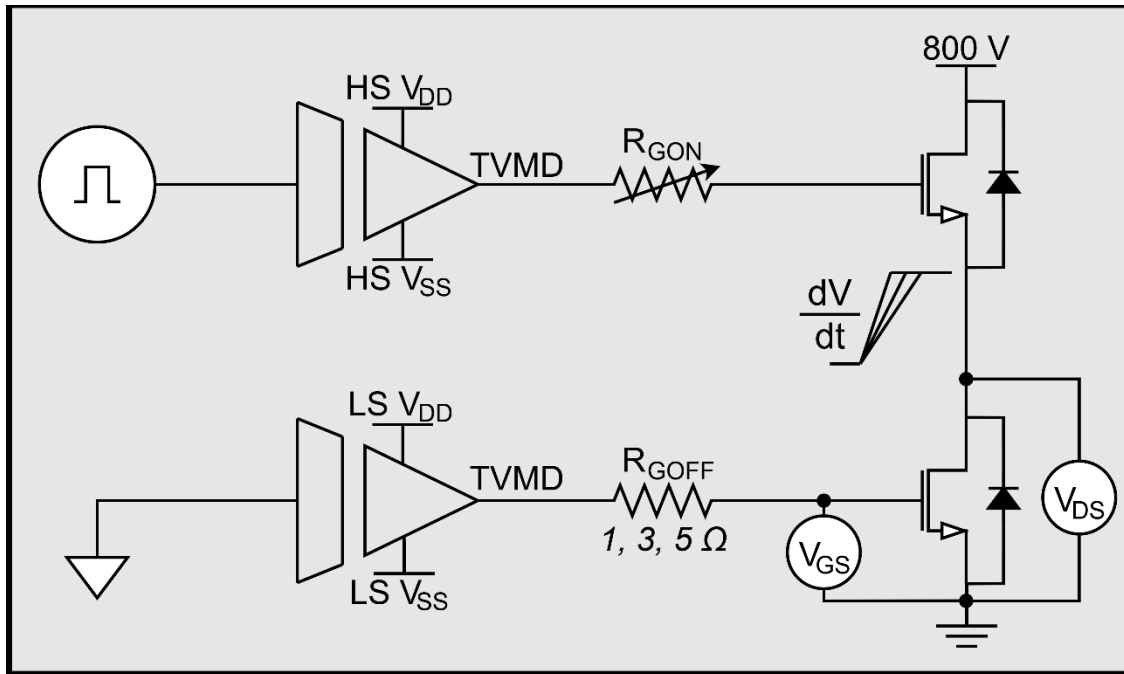
- SPD± pin controls output current for V_{OH} and V_{OL}
 - Analog voltage input or resistor
- Output die demodulates SPD± information over channel
- Output current sources change the source/sink current
- Miller clamp is setting the sinking current source to max current sink

Miller Clamp Engagement Waveform

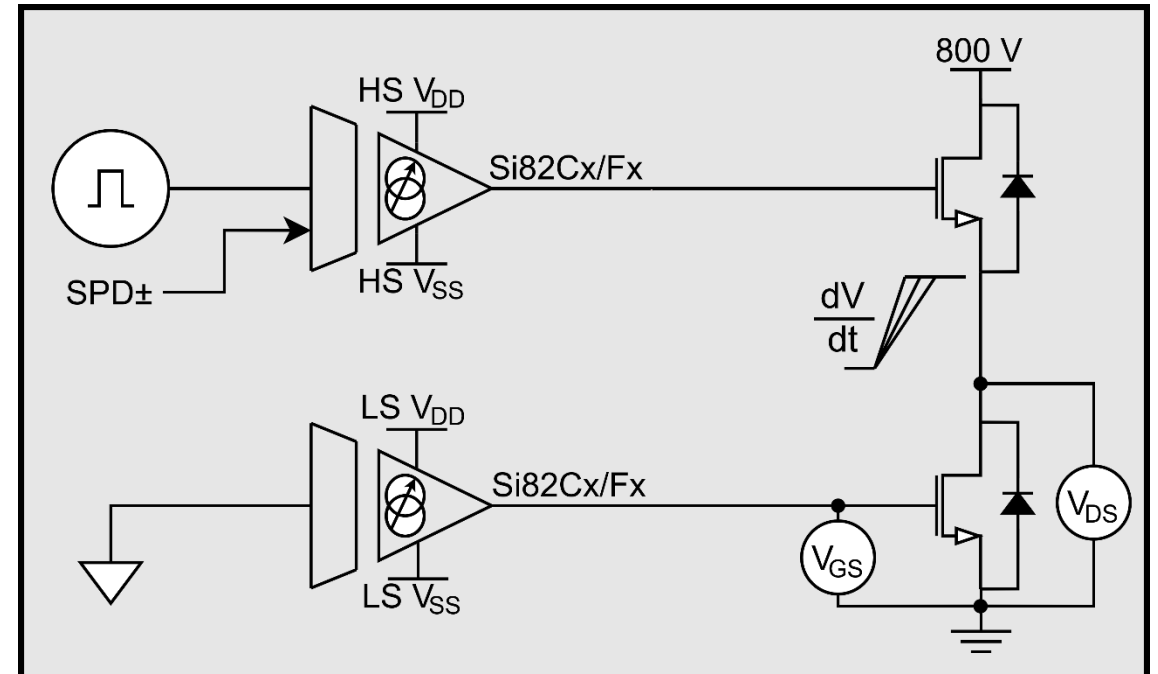


Test Setup – 1200V 16 mΩ SiCFET

Traditional Voltage Mode Driver
6 A – $R_{ON} = 0.7 \Omega$



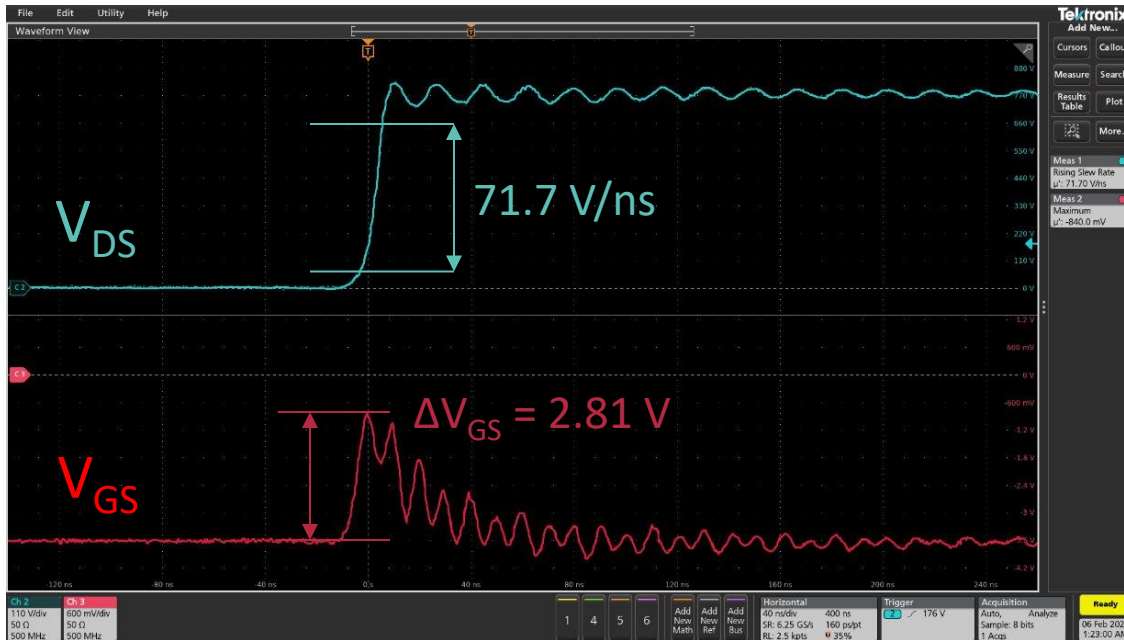
SeIVCD™ Gate Driver
4 A



Low Side V_{DS} and V_{GS} Waveforms

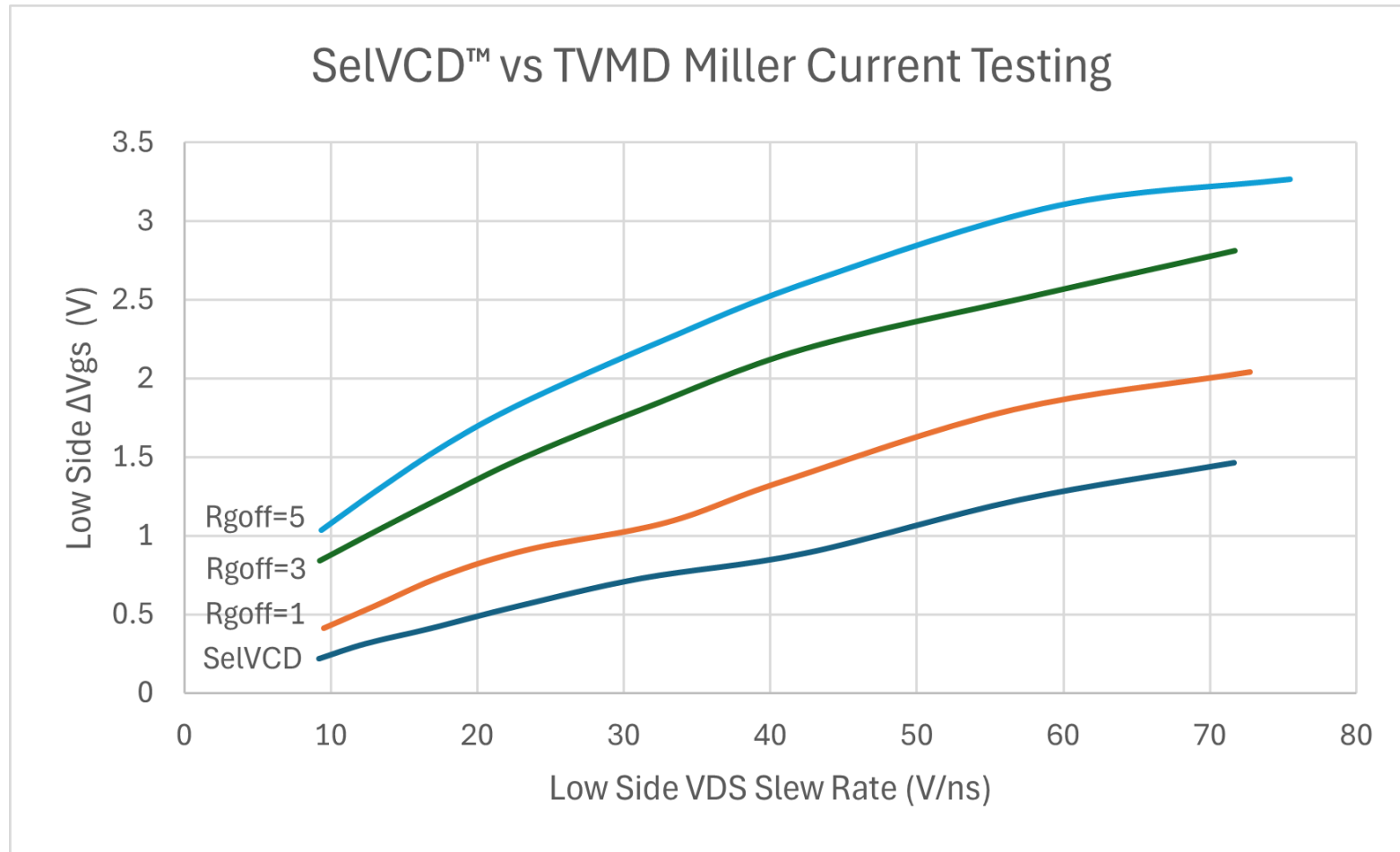
TVMD $R_{G\text{OFF}} = 3 \Omega$

SeIVCD™



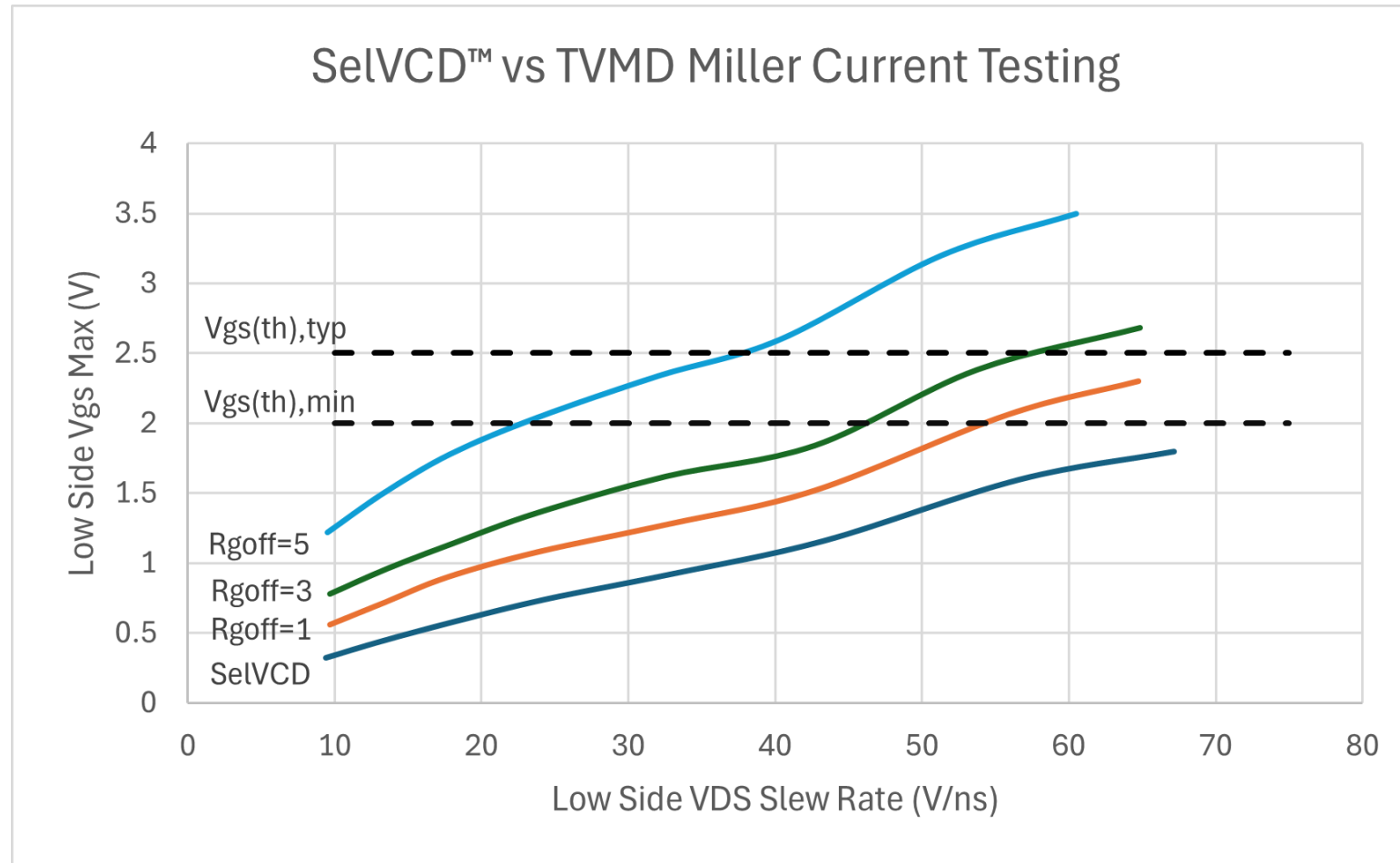
$$V_{GS,ON} = 15 \text{ V}, V_{GS,OFF} = -3.5 \text{ V}$$

ΔV_{GS} vs V_{DS} Slew Rate Results – Negative Bias



$$V_{GS,ON} = 15 \text{ V}, V_{GS,OFF} = -3.5 \text{ V}$$

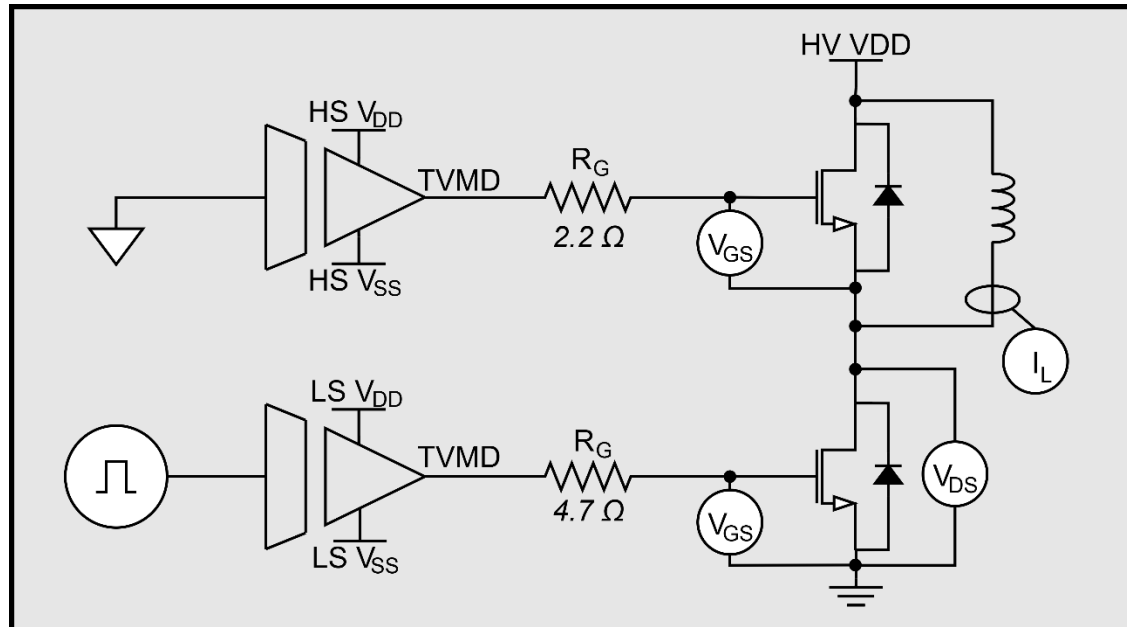
V_{GS} vs V_{DS} Slew Rate Results – 0 V Bias



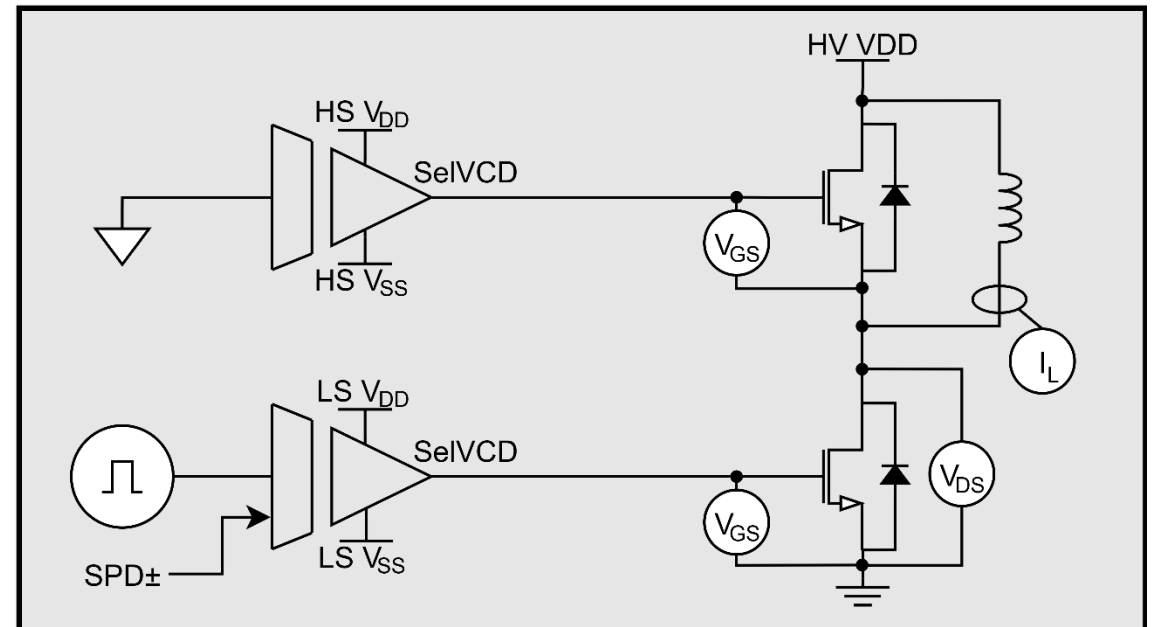
$$V_{GS,ON} = 15 \text{ V}, V_{GS,OFF} = 0 \text{ V}$$

750 V SiC - Customer Test Setup $V_{GS} = +18.5/0 \text{ V}$

Si82E39ABE-IS3

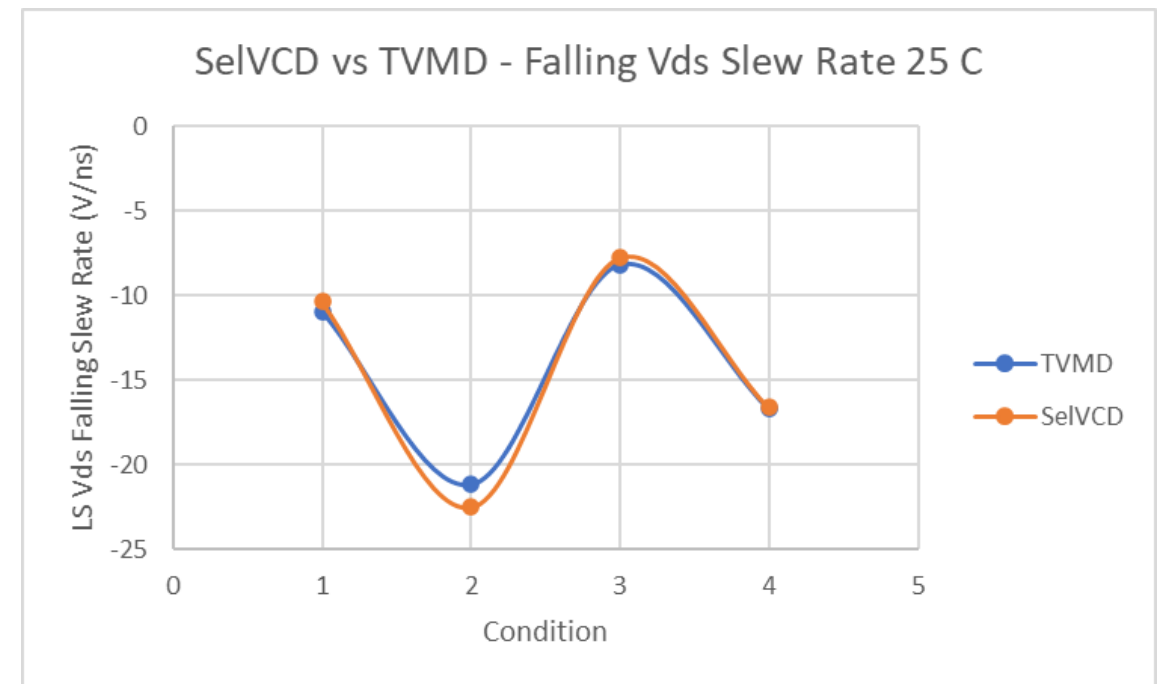
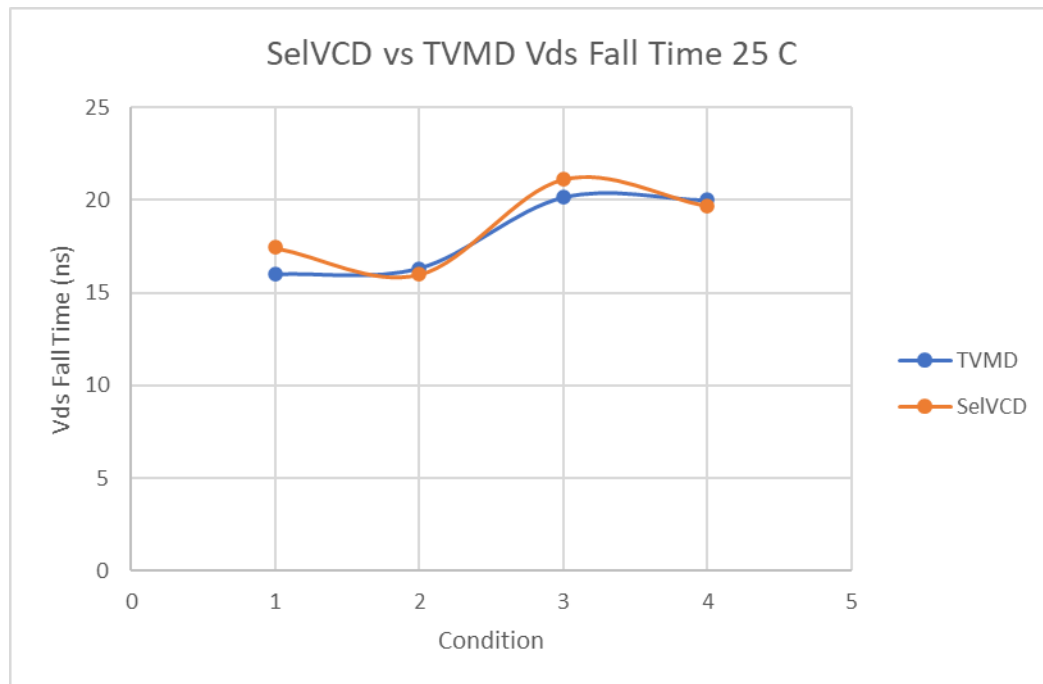


Si82F39AEE-IS3

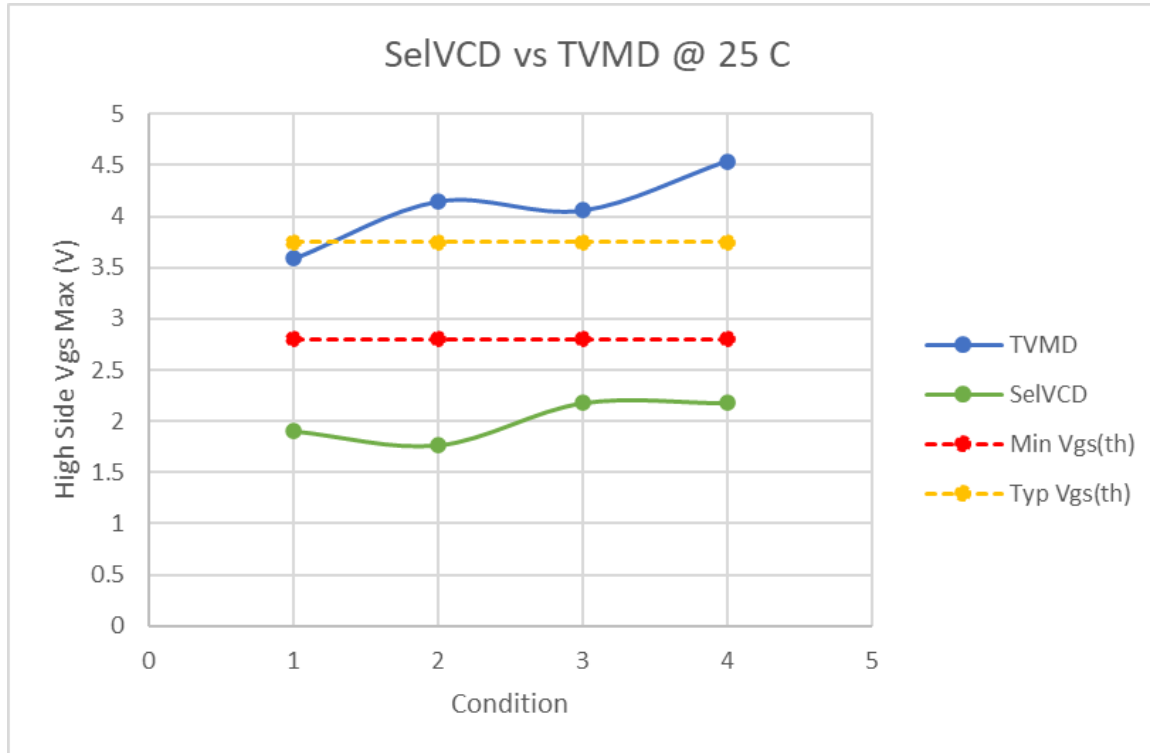


TVMD vs SelVCD Customer Comparison

- Condition 1 = 227 V 25 A
- Condition 2 = 455 V 25 A
- Condition 3 = 227 V 45 A
- Condition 4 = 455 V 45 A



High Side V_{GS} Max



- Condition 1 = 227 V 25 A
- Condition 2 = 455 V 25 A
- Condition 3 = 227 V 45 A
- Condition 4 = 455 V 45 A
- Current R_G selections result in max HS V_{GS} significantly above min $V_{GS(th)}$
- SeIVCD stays well below $V_{GS(th)}$

Conclusions

- SelVCD™ minimizes the risk of parasitic turn-on
- Allows removal of negative gate-drive bias, providing additional safety margin
 - Lowers BOM cost
 - Frees up valuable board space
 - Improves overall system efficiency
- Traditional voltage-mode drivers may require a Miller clamp, adding pins and increasing BOM/cost
 - SelVCD achieves this with no extra pins or added components



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Appendix – Derivation

- Capacitive voltage divider equation: $\frac{V_{out}}{V_{in}} = \frac{C_1}{C_1+C_2}$
 - In the case of the Miller effect, $C_1 = C_{GD}$ and $C_2 = C_{GS}$
 - $\frac{V_{GS}}{V_{DS}} = \frac{C_{GD}}{C_{GS}+C_{GD}}$, however $C_{GD} \ll C_{GS}$ so the following simplification can be made: $\frac{V_{GS}}{V_{DS}} = \frac{C_{GD}}{C_{GS}}$
 - The main contribution to PTO, is the mostly constant slope from V_{DS} . Only need to consider the slew rate of the rising and falling edges: $\frac{dV_{GS}}{dV_{DS}} = \frac{C_{GD}}{C_{GS}} \Rightarrow dV_{GS} \approx \frac{C_{GD}}{C_{GS}} dV_{DS}$